

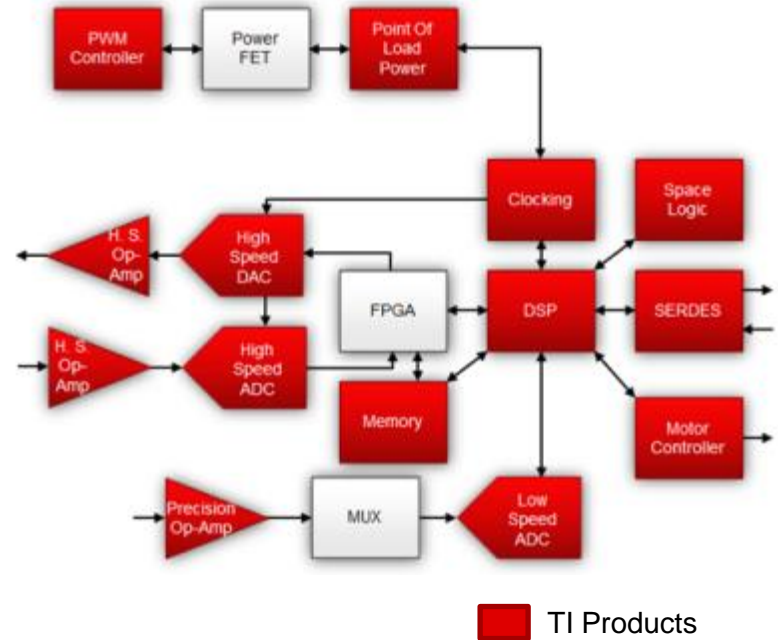
# Texas Instruments Enabling New Space

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# TI's Dedication to Space Market

- TI IC's are aboard **every space shuttle ever launched** and most payloads up to this day.
- **Longevity**
  - 60 years experience in the Space Market
- **Supporting long product life cycles**
  - Selling parts designed > 30 years ago
  - No obsolescence for convenience
- **Global company**
  - 8 QMLV-certified wafer fabs and growing
  - Dozens of Design Centers around the Globe
- **TI investing to grow Space business**

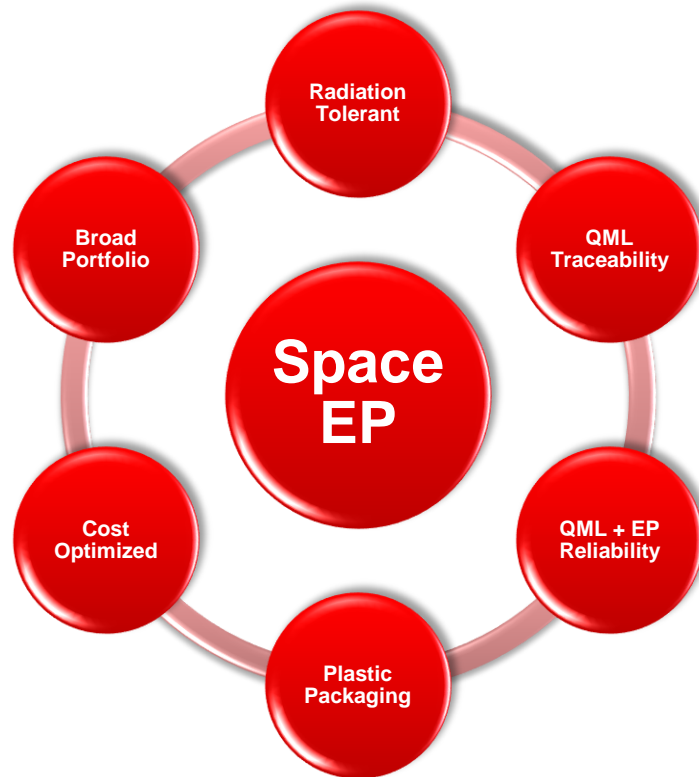


# Texas Instruments Space EP for New Space



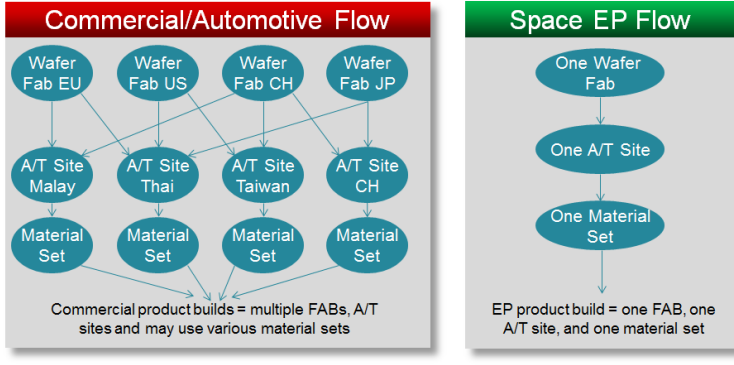
# What is Space EP?

- Cost effective, high performance radiation **tolerant** solution for **shorter** duration **high volume** small satellites
- **Space EP = Traceability + Reliability + Radiation**
  - QMLV like flow
    - Wafer lot accept
    - Traceability
  - Radiation
    - RHA Qualification: **20k rad**
    - SEL Characterization : **43MeV**
  - Extra tests for qualification, production and lot acceptance
  - Enhanced Products Reliability
    - Robust material set (lead frame, mold compound, bond wire, etc..)
    - Enhanced qualification (HAST, extended temperature, meets MIL-PRF 38535 Class N)



# TI's Space EP Advantages

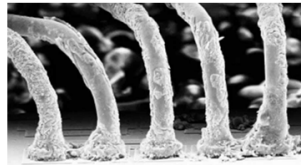
## Space EP Baseline Controlled Flow



## Cu Bond Wire Concerns

Most of COTS products now use Copper  
Risk with Copper wire

- Bond integrity (Cu bonding to aluminum)<sup>1</sup>
- Corrosion due to mold compound interaction<sup>2</sup>
- Higher failure rate due to bondwire neck breaks during temperature cycling (The coefficient of thermal expansion [CTE] of Cu is higher than Au)<sup>3</sup>



Sources:  
<sup>1</sup> Luke England and Tom Jiang, "Reliability of Cu Wire Bonding to Al Metallization", Electronic Components and Technology Conference, 2007.  
<sup>2</sup> Hui Teng, et al, "Effect of Moisture and Temperature on Al-Cu Interfacial Strength", International Conference on Electronic Packaging Technology & High Density Packaging, 2008.  
<sup>3</sup> Bart Vanderveide and Geert Willems, "Early fatigue failures in Copper wire bonds inside packages with low CTE Green Mold Compounds", 4<sup>th</sup> ESTC Conference, 2012, Amsterdam, The Netherlands.

**Space EP devices use gold bond wire**

## Variability of TID

COTS devices

- Tested for electrical performance
- No test for radiation → Even though TID might be good on devices from same wafer, it can drastically change on another wafer
- Once devices shipped from Semiconductor supplier, not possible to distinguish from one wafer to other

**Radiation Lot Acceptance Testing (RLAT) for Space EP Devices**

Lot-to-Lot variation impact on HDR TID

Example device	HDR TID (krad)	Status
Lot #1	100	Pass
Lot #2	30	Pass
Lot #3	10	Fail

Wafer-to-Wafer impact on LDR TID

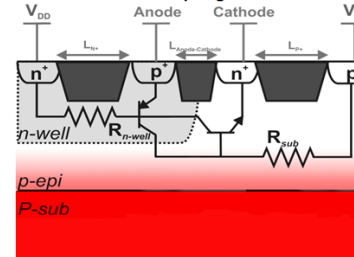
Example device	LDR TID (krad)	Status
Wafer #2	80	Pass
Wafer #3	50	Pass
Wafer #15	30	Fail

## Key Sources of Variability for SEL

- EPI thickness
- EPI doping
- Substrate doping

**Example device: Exhibits SEL based on 0.5um variation**

EPI (um)	Temp	LET	SEL
Commer.	25	60	Yes
9.5	25	85	No
9.5	125	85	No
10	25	85	Yes
10	125	60	Yes



**EPI parameters controlled tightly for Space EP flow**

# TI's Range of Solutions

Quality / Reliability / Cost

	Commercial	Q100	EP	QMLQ	SEP	QMLV	
						QMLV	QMLV-RHA
<b>Packaging</b>	Plastic	Plastic	Plastic	Ceramic	Plastic	Ceramic	Ceramic
<b>Single Controlled Baseline</b>	No	No	Yes	Yes	Yes	Yes	Yes
<b>Bond Wires</b>	Au/Cu	Au/Cu	Au	Al	Au	Al	Al
<b>Is Pure Sn used?</b>	Yes	Yes	No	No	No	No	No
<b>Production Burnin</b>	No	No	No	No	No	Yes	Yes
<b>Typical Temperature Range</b>	-40°C - 85°C	-40°C - 125°C	-55°C - 125°C (majority)	-55°C - 125°C	-55°C - 125°C (majority)	-55°C - 125°C	-55°C - 125°C
<b>Radiation (SEL/SEE)</b>	No	No	No	No	Yes	Yes	Yes
<b>Radiation (TID) Lot Acceptance (RLAT)</b>	No	No	No	No	Yes	No	Yes
<b>Lot Level Temp Cycle</b>	No	No	No	Group D	Lot Level	Group D	Group D
<b>Lot Level HAST</b>	No	No	No	N/A	Yes	N/A	N/A
<b>Life Test Per Wafer Lot</b>	No	No	No	No	No	Yes	Yes

# Upcoming Space EP Devices

Power

Precision  
ADC

Op Amp

Comparator

Interface

Current  
Sensor

$\mu$ Controller

Many More!

Development on-going for different product types. Contact TI for more details.

# Thank You!

CCR 1235C  
PS50604-RFHK  
THA

